

PROCEEDINGS OF SPIE

Optical Micro- and Nanometrology VII

**Christophe Gorecki
Anand Krishna Asundi
Wolfgang Osten**
Editors

**25–26 April 2018
Strasbourg, France**

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Published by
SPIE

Volume 10678

Proceedings of SPIE 0277-786X, V. 10678

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

Optical Micro- and Nanometrology VII, edited by Christophe Gorecki, Anand Krishna Asundi,
Wolfgang Osten, Proc. of SPIE Vol. 10678, 1067801 · © 2018 SPIE
CCC code: 0277-786X/18/\$18 · doi: 10.1117/12.2503291

Proc. of SPIE Vol. 10678 1067801-1

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Author(s), "Title of Paper," in *Optical Micro- and Nanometrology VII*, edited by Christophe Gorecki, Anand Krishna Asundi, Wolfgang Osten, Proceedings of SPIE Vol. 10678 (SPIE, Bellingham, WA, 2018) Seven-digit Article CID Number.

ISSN: 0277-786X
ISSN: 1996-756X (electronic)

ISBN: 9781510618824
ISBN: 9781510618831 (electronic)

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445

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Contents

vii *Authors*
ix *Conference Committee*

SESSION 1 INTERFEROMETRY I

- 10678 02 **Speckle Interferometry in harsh environments: design considerations and successful examples (Invited Paper)** [10678-1]
- 10678 04 **Focusing type grating interferometer** [10678-3]
- 10678 05 **Perturbation resistant RGB-interferometry with pulsed LED illumination (Best Student Paper Award)** [10678-4]
- 10678 06 **Laser heterodyne interferometer for simultaneous measurement of displacement, and roll-angle based on the acousto-optic modulators** [10678-5]

SESSION 2 OPTICAL TOMOGRAPHY

- 10678 07 **The SS-OCT endomicroscopy probe based on MOEMS Mirau micro-interferometer for early stomach cancer detection (Invited Paper)** [10678-6]
- 10678 0A **The original application of hybrid lens in micromasurements for optical coherence tomography** [10678-9]

SESSION 3 METROLOGY OF MICROOPTICS/MEMS

- 10678 0B **Assessing microlens quality based on 3D irradiance measurement at the focal spot area** [10678-10]
- 10678 0C **About detecting steam condensation by means of polymer racetrack micro-resonators: highlighting the dynamics of such a soft matter process** [10678-11]
- 10678 0E **Lithographic diffraction grating with a period failure** [10678-14]

SESSION 4 HOLOGRAPHY

- 10678 0F **Holographic characterization and laser structuring of a microphone membrane** [10678-16]

10678 OH **Size measurements of an optical fiber by diffraction pattern analysis in Fraunhofer approximation** [10678-18]

SESSION 5 OPTICAL SCATTEROMETRY

10678 OJ **Multimodal imaging Mueller polarimetric microscope to study polarimetric properties of spheroidal microparticles** [10678-20]

SESSION 6 MICRO- AND NANOTOPOGRAPHY

10678 OL **Application of coherence scanning interferometry for local spectral characterization of transparent layers** [10678-22]

10678 OM **Residual flatness error correction in three-dimensional imaging confocal microscopes** [10678-23]

10678 ON **GPU-accelerated simulation of the superresolution capabilities of dielectric microspheres using the Differential Method** [10678-24]

10678 OO **Determination of structural deviations in wire grid polarizers for DUV application wavelengths by transmission spectroscopy in the visible spectral range** [10678-25]

SESSION 7 INTERFEROMETRY II

10678 OQ **Interferometric measuring systems of nanopositioning and nanomeasuring machines (Invited Paper)** [10678-27]

10678 OR **Dispersion-controlled low-coherent interferometry for thin-film characterization** [10678-28]

10678 OS **Ultrastable metrology laser at 633 nm using an optical frequency comb** [10678-29]

10678 OT **Symmetrical double diffraction laser encoder** [10678-30]

10678 OV **Two-step phase shifting in fringe projection: modeling and analysis** [10678-32]

SESSION 8 SPECIALIZED TECHNIQUES

10678 OW **Mapping of the detecting units of the resonator-based multiplexed sensor** [10678-33]

10678 OX **Numerical analysis of angle-selective one-dimensional periodic structure for building energy management** [10678-34]

10678 0Y **Effects of non-ideal display properties in phase measuring deflectometry: A model-based investigation** [10678-35]

10678 0Z **Ultra-small mechanical deformation sensor using a hybrid fiber optic-based triangular photonic crystal structure** [10678-36]

POSTER SESSION

10678 10 **Pump-probe digital holography for monitoring of long bulk nonlinear strain waves in solid waveguides** [10678-37]

10678 12 **Optical challenging feature inline measurement system based on photometric stereo and HON feature extractor** [10678-39]

10678 14 **Micro Glass Blowing platform for microfabrication of microoptical components** [10678-42]

10678 15 **Step-index optical fiber sizing with a rainbow technique** [10678-43]

10678 16 **Immersion white light scanning interferometry using elastic polymer path length compensation** [10678-44]

10678 18 **Deriving forces in a single beam gradient force optical tweezers using the angular spectrum method** [10678-13]

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Albertazzi, A., 02
Anstotz, Freddy, 16
Artigas, Roger, 0M
Bargiel, Sylwester, 07, 14
Barillon, Rémi, 16
Barrera, E. S., 02
Bartsch, Jonas, 0Y
Bêche, B., 0C
Béguelin, Jeremy, 0B
Beiu, Roxana-Mariana, 0Z
Beiu, Valeriu, 0Z
Belashov, A. V., 10
Beltukov, Y. M., 10
Benedet, M., 02
Berges, M., 0C
Bergmann, Ralf B., 0Y
Bermudez, Carlos, 0M
Billard, Alain, 07
Blumröder, Ulrike, 0S
Bodermann, B., 0O
Boukellal, A., 0H
Boumrrar, K., 0H
Cadevall, Cristina, 0M
Carrion, J. Vincente, 14
Cazin, V., 0C
Chen, Howard, 12
Chutani, Ravinder, 07
Claveau, R., 0L
Cormerais, H., 0C
Dickmann, J., 0O
Dickmann, W., 0O
Drozella, Johannes, 0N
Duma, Virgil-Florin, 0Z
Ebisawa, Mizue, 0X
Egorov, D. I., 0A
Fantin, A. V., 02
Felgner, André, 0M
Fernández, Andrea, 0J
Flury, M., 0L
Frenner, Karsten, 0N
Gao, Jianmin, 06
Garcia-Caurel, Enric, 0J
Garnier, L., 0C
Gaviot, E., 0C
Głomb, Grzegorz, 15
Gorecki, Christophe, 07, 14
Hartmann, P., 0F, 0R
Hausotte, Tino, 0Q
He, Pei-Yun, 0T
Healy, John J., 18
Hennelly, Bryan M., 18
Hsieh, Hung-Lin, 04, 0T
Huang, Junhui, 06
Isoda, Kazutaka, 0X
Jacobs, P., 0F
Kalms, Michael, 0Y
Köchert, Paul, 0S
Kroker, S., 0O
Lehmann, Peter, 05
Lhermite, H., 0C
Li, Dechun, 0V
Li, Q., 0C
Liang, An-Jie, 0T
Liao, Jia-Xian, 04
Liu, Huiyu, 12
Lu, Lei, 0V
Lushnikov, D. S., 0E
Manske, Eberhard, 0S
Mao, Jiaqi, 0V
Martinez, Pol, 0M
Matilla, Aitor, 0M
Meng, Xiangfeng, 0V
Mokdad, R., 0H
Montgomery, Paul C., 0L, 16
Moreno, Fernando, 0J
Mukhtar, Husneni, 16
Nagata, Kohki, 0X
Nelsen, B., 0F, 0R
Noell, Wilfried, 0B
Nüß, Johann R., 0Y
Odinokov, S. B., 0E
Ossikovski, Razvigor, 0J
Osten, Wolfgang, 0N
Ostendorf, Andreas, 0W
Otani, Yukitoshi, 0X
Pape, Christian, 0V
Passilly, Nicolas, 07, 14
Pfeiffer, P., 0H
Preuß, M., 0R
Prinzler, Martin H. U., 0Y
Qi, Jingya, 06
Reithmeier, Eduard, 0V
Rojas Hurtado, C. B., 0O
Rubin, Anne, 16
Rudek, F., 0F
Saetchnikov, Anton, 0W
Saetchnikov, Vladimir, 0W
Saiz, Jose Maria, 0J

Schake, Markus, 05
Scharf, Toralf, 0B
Semenova, I. V., 10
Shishova, M. V., 0E
Siefke, T., 0O
Silva, F., 02
Song, Kechen, 12
Steinert, M., 0O
Struk, Przemyslaw, 07
Sun, Bo-Yen, 04
Świrniak, Grzegorz, 15
Symeonidis, Michail, 0B
Tanguy, Quentin A. A., 07
Taudt, Ch., 0F, 0R
Tcherniavskaia, Elina, 0W
Veiga, C. L., 02
Vié, V., 0C
Viotti, M. R., 02
Voelkel, Reinhard, 0B
Wang, Zhao, 06
Weichelt, T., 0O
Weiss, J., 0C
Willemann, D. P., 02
Xie, Huikai, 07
Yan, Yunhui, 12
Yang, Xiulun, 0V
Yin, Yongkai, 0V
Yoo, Thomas Sang Hyuk, 0J
Yu, Qin, 18
Zherdev, A. Y., 0E

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Wolfgang Osten, Institut für Technische Optik (Germany)
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